MOSFET – Power, Single N-Channel, D2PAK

650 V, 110 mΩ, 30 A

Description

SUPERFET® III MOSFET is ON Semiconductor's brand-new high voltage super-junction (SJ) MOSFET family that is utilizing charge balance technology for outstanding low on-resistance and lower gate charge performance. This advanced technology is tailored to minimize conduction loss, provide superior switching performance, and withstand extreme dv/dt rate.

Consequently, SUPERFET III MOSFET is very suitable for the various power system for miniaturization and higher efficiency. SUPERFET III FRFET® MOSFET's optimized reverse recovery performance of body diode can remove additional component and improve system reliability.

Features

- $700 \text{ V} @ \text{T}_{\text{J}} = 150^{\circ}\text{C}$
- Typ. $R_{DS(on)} = 93 \text{ m}\Omega$
- Ultra Low Gate Charge (Typ. Q_g = 58 nC)
- Low Effective Output Capacitance (Typ. Coss(eff.) = 533 pF)
- 100% Avalanche Tested
- Qualified with AEC-Q101
- These Devices are Pb-Free and are RoHS Compliant

Typical Applications

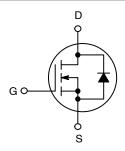
- Automotive On Board Charger
- Automotive DC/DC Converter for HEV



ON Semiconductor®

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V _{(BR)DSS}	R _{DS(ON)} MAX	I _D MAX		
650 V	110 m Ω @ 10 V	30 A		

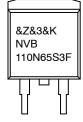


N-CHANNEL MOSFET



D²PAK-3 TO-263 CASE 418AJ

MARKING DIAGRAM



&Z = Assembly Plant Code &3 = Data Code (Year & Week)

&K = Lot

NVB110N65S3F = Specific Device Code

ORDERING INFORMATION

See detailed ordering and shipping information on page 8 of this data sheet.

Table 1. ABSOLUTE MAXIMUM RATINGS (T_C = 25°C unless otherwise stated)

Symbol	Parameter	Value	Unit	
V _{DSS}	Drain-to-Source Voltage	650	V	
V_{GS}	Gate-to-Source Voltage	- DC	±30	V
		– AC (f > 1 Hz)	±30	1
I _D	Drain Current	– Continuous (T _C = 25°C)	30	Α
		– Continuous (T _C = 100°C)	19.5	1
I _{DM}	Drain Current	- Pulsed (Note 1)	69	Α
E _{AS}	Single Pulse Avalanche Energy (Note 2)		380	mJ
I _{AS}	Avalanche Current Repeated Avalanche Energy (Note 1)		3.5	Α
E _{AR}			2.4	mJ
dv/dt	v/dt MOSFET dv/dt		100	V/ns
	Peak Diode Recovery dv/dt (Note 3)	50	1	
P_{D}	Power Dissipation	Tc = 25°C	240	W
		- Derate Above 25°C	1.92	W/°C
T _J , T _{stg}	Operating Junction and Storage Temperature Maximum Lead Temperature for Soldering, 1/8" from Case for 5 Seconds		–55 to 150	°C
T _L			300	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

1. Repetitive rating: pulse – width limited by maximum junction temperature.

2. IAS = 3.5 A, RG = 25 Ω, starting T_J = 25°C.

3. ISD ≤ 15 A, di/dt ≤ 200 A/_s, V_{DD} ≤ 400 V, starting T_C = 25°C.

Table 2. THERMAL RESISTANCE RATINGS

Symbol	Parameter	Max	Unit
$R_{ heta JC}$	Thermal Resistance, Junction-to-Case, Max.	0.52	°C/W
$R_{ heta JA}$	Thermal Resistance, Junction-to-Ambient, Max.	40	

ELECTRICAL CHARACTERISTICS (T_C = 25°C unless otherwise noted)

Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
OFF CHARAC	TERISTICS			•	•	
BV _{DSS}	Drain-to-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 1 \text{ mA}, T_J = 25^{\circ}\text{C}$	650	-	_	V
		$V_{GS} = 0 \text{ V}, I_D = 10 \text{ mA}, T_J = 150^{\circ}\text{C}$	700	-	-	V
$\Delta BV_{DSS}/\Delta T_{J}$	Breakdown Voltage Temperature Coefficient	I _D = 20 mA, Referenced to 25°C	_	0.61	-	V/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 650 V, V _{DS} = 0 V	1	-	10	μΑ
		V _{DS} = 520 V, T _C = 125°C	-	128	-	μΑ
I _{GSS}	Gate-to-Body Leakage Current	$V_{GS} = 0 \text{ V}, I_D = 1 \text{ mA}, T_J = 25^{\circ}\text{C}$	1	-	±100	nA
ON CHARACT	ERISTICS				•	-
V _{GS(th)}	Drain-to-Source Breakdown Voltage	$V_{GS} = V_{DS}$, $I_D = 3 \text{ mA}$	3.0	-	5.0	V
R _{DS(on)}	Static Drain-to-Source On Resistance	V _{GS} = 10 V, I _D = 15 A	-	93	110	mΩ
9FS	Forward Transconductance	V _{GS} = 20 V, I _D = 15 A	_	17	-	S
DYNAMIC CH	ARACTERISTICS				•	-
C _{iss}	Input Capacitance	V _{DS} = 400 V, V _{GS} = 0 V, f = 1 MHz	-	2560	_	pF
C _{oss}	Output Capacitance		-	50	-	pF
C _{oss(eff.)}	Effective Output Capacitance	V _{DS} = 0 to 400 V, V _{GS} = 0 V	1	553	-	pF
C _{oss(er.)}	Energy Related Output Capacitance	V _{DS} = 0 to 400 V, V _{GS} = 0 V	-	83	-	pF
Q _{g(total)}	Total Gate Charge at 10 V	V _{DS} = 400 V, I _D = 15 A, V _{GS} = 10 V (Note 4)	-	58	-	nC
Q _{gs}	Gate-to-Source Gate Charge		-	19	-	nC
Q _{gd}	Gate-to-Drain "Miller" Charge		-	23	-	nC
ESR	Equivalent Series Resistance	F = 1 MHz	-	2	-	Ω
WITCHING C	CHARACTERISTICS, V _{GS} = 10 V					
t _{d(on)}	Turn-On Delay Time	$V_{DD} = 400 \text{ V}, I_D = 15 \text{ A},$	-	29	-	ns
t _r	Rise Time	$V_{GS} = 10 \text{ V}, R_{G} = 4.7 \Omega$ (Note 4)	-	32	-	ns
t _{d(off)}	Turn-Off Delay Time		1	61	-	ns
t _f	Fall Time		1	16	-	ns
SOURCE-DRA	AIN DIODE CHARACTERISTICS					
Is	Maximum Continuous Source-to-Drain Diode Forward Current		-	_	30	Α
I _{SM}	Maximum Pulsed Source-to-Drain Diode Forward Current		-	-	69	Α
V _{SD}	Source-to-Drain Diode Forward Voltage	V _{GS} = 0 V, I _{SD} = 15 A	-	_	1.3	V
t _{rr}	Reverse-Recovery Time	V _{GS} = 0 V, I _{SD} = 15 A,	_	94	-	ns
Q _{rr}	Reverse-Recovery Charge	dI _F /dt = 100 A/μs	-	343	-	nC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

4. Essentially independent of operating temperature typical characteristics.

TYPICAL CHARACTERISTICS

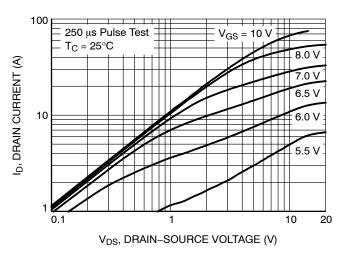


Figure 1. On–Region Characteristics 25°C

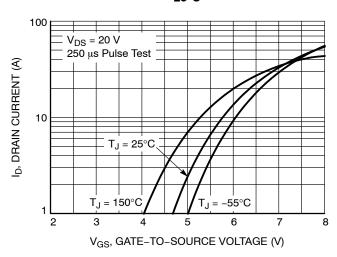


Figure 3. Transfer Characteristics

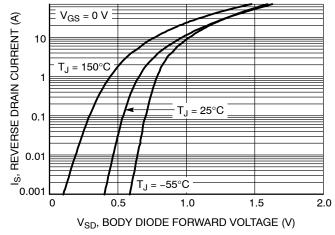


Figure 5. Body Diode Forward Voltage Variation vs. Source Current and Temperature

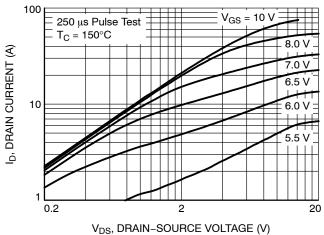


Figure 2. On–Region Characteristics

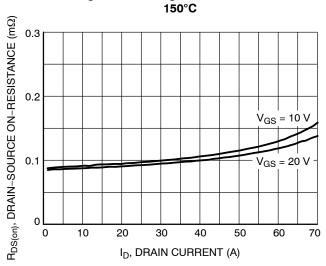


Figure 4. On–Resistance Variation vs. Drain Current and Gate Voltage

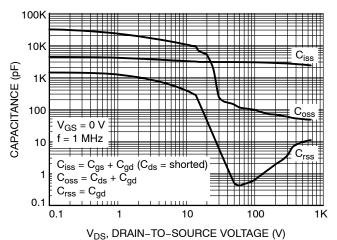


Figure 6. Capacitance Characteristics

TYPICAL CHARACTERISTICS

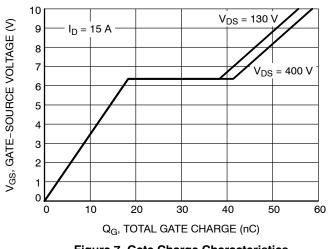


Figure 7. Gate Charge Characteristics

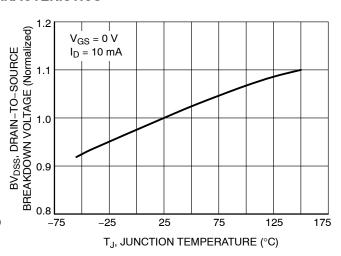


Figure 8. Breakdown Voltage Variation vs.
Temperature

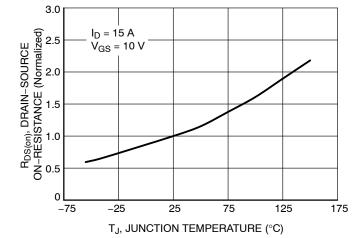


Figure 9. On–Resistance Variation vs.
Temperature

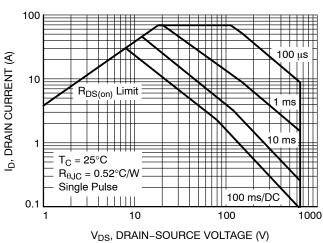


Figure 10. Maximum Safe Operating Area

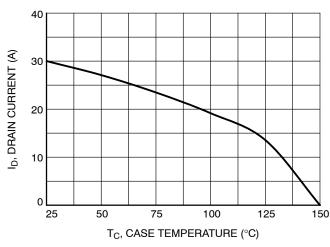


Figure 11. Maximum Drain Current vs. Case Temperature

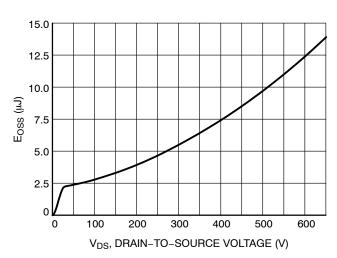


Figure 12. E_{OSS} vs. Drain-to-Source Voltage

TYPICAL CHARACTERISTICS

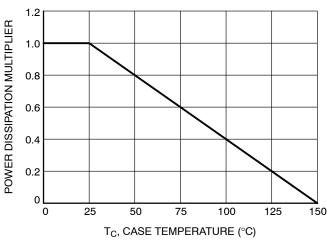


Figure 13. Normalized Power Dissipation vs.

Case Temperature

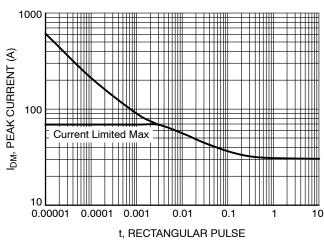


Figure 14. Peak Current Capability

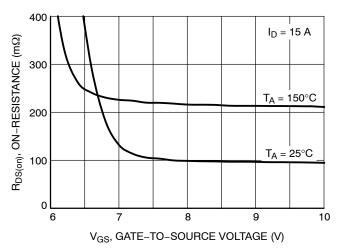


Figure 15. R_{DS(on)} vs. Gate Voltage

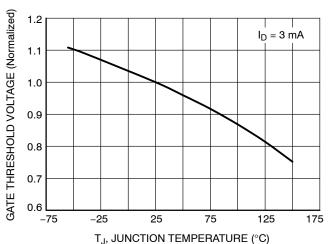


Figure 16. Normalized Gate Threshold Voltage vs. Temperature

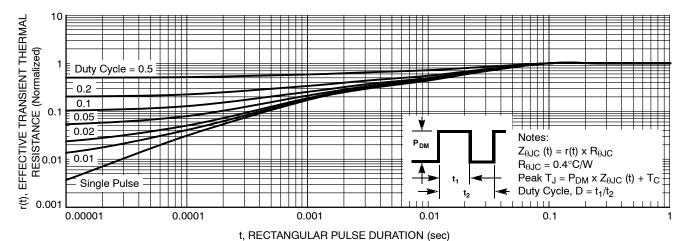
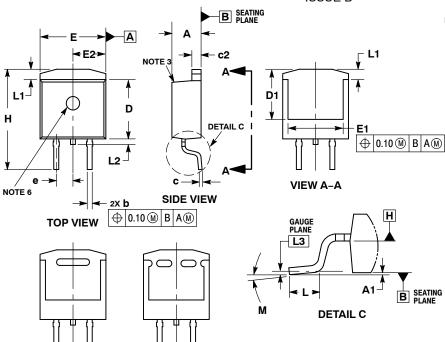


Figure 17. Transient Thermal Response

PACKAGE DIMENSIONS

D²PAK-3 (TO-263, 3-LEAD) CASE 418AJ **ISSUE B**



VIEW A-A
OPTIONAL CONSTRUCTIONS

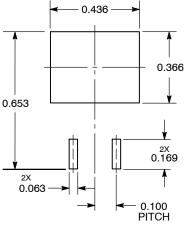
NOTES:

- NOTES:

 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
 2. CONTROLLING DIMENSION: INCHES.
 3. CHAMFER OPTIONAL
 4. DIMENSIONS D AND E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED 0.005 PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY AT DATUM H.
 5. THERMAL PAD CONTOUR IS OPTIONAL WITHIN DIMENSIONS E, L1, D1 AND E1.
 6. OPTIONAL MOLD FEATURE

	INC	HES	MILLIN	IETERS	
DIM	MIN	MAX	MIN	MAX	
Α	0.160	0.190	4.06	4.83	
A1	0.000	0.010	0.00	0.25	
b	0.020	0.039	0.51	0.99	
С	0.012	0.029	0.30	0.74	
c2	0.045	0.065	1.14	1.65	
D	0.330	0.380	8.38	9.65	
D1	0.260		6.60		
E	0.380	0.420	9.65	10.67	
E1	0.245	5 6.22			
е	0.100	BSC	2.54 BSC		
Н	0.575	0.625	14.60	15.88	
L	0.070	0.110	1.78	2.79	
L1		0.066		1.68	
L2		0.070		1.78	
L3	0.010 BSC		0.25 BSC		
М	0°	8°	0°	8°	

RECOMMENDED SOLDERING FOOTPRINT*



DIMENSIONS: INCHES

^{*}For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

PACKAGE MARKING AND ORDERING INFORMATION

Part Number	Top Marking	Package	Packing Method	Reel Size	Tape Width	Quantity
NVB110N65S3F	NVB110N65S3F	D ² PAK	Tape & Reel [†]	330 mm	24 mm	800 Units

[†]For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

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